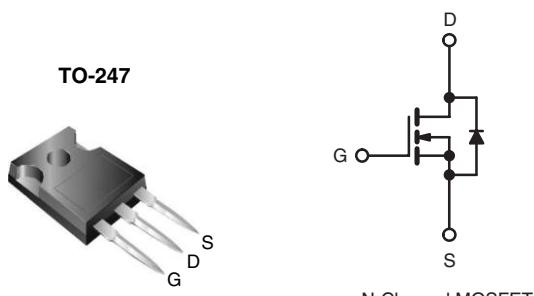


Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	600	
$R_{DS(on)}$ (Ω)	$V_{GS} = 10$ V	0.40
Q_g (Max.) (nC)	120	
Q_{gs} (nC)	29	
Q_{gd} (nC)	48	
Configuration	Single	



FEATURES

- Ultra Low Gate Charge
- Reduced Gate Drive Requirement
- Enhanced 30 V V_{GS} Rating
- Reduced C_{iss} , C_{oss} , C_{rss}
- Isolated Central Mounting Hole
- Dynamic dV/dt Rated
- Repetitive Avalanche Rated
- Lead (Pb)-free Available


RoHS*
COMPLIANT

DESCRIPTION

This new series of low charge Power MOSFETs achieve significantly lower gate charge over conventional MOSFETs. Utilizing advanced Power MOSFETs technology the device improvements allow for reduced gate drive requirements, faster switching speeds and increased total system savings. These device improvements combined with the proven ruggedness and reliability of Power MOSFETs offer the designer a new standart in power transistors for switching applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.

ORDERING INFORMATION

Package	TO-247
Lead (Pb)-free	IRFPC60LCPbF SiHFPC60LC-E3
SnPb	IRFPC60LC SiHFPC60LC

ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V_{DS}	600	
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current	I_D	16	
		10	A
Pulsed Drain Current ^a	I_{DM}	64	
Linear Derating Factor		2.2	W/°C
Single Pulse Avalanche Energy ^b	E_{AS}	1000	mJ
Repetitive Avalanche Current ^a	I_{AR}	16	A
Repetitive Avalanche Energy ^a	E_{AR}	28	mJ
Maximum Power Dissipation	P_D	280	W
Peak Diode Recovery dV/dt ^c	dV/dt	3.0	V/ns
Operating Junction and Storage Temperature Range	T_J , T_{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	
Mounting Torque	6-32 or M3 screw	10	lbf · in
		1.1	N · m

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = 25$ V, starting $T_J = 25$ °C, $L = 7.2 \mu\text{H}$, $R_G = 25 \Omega$, $I_{AS} = 16$ A (see fig. 12).
- $I_{SD} \leq 16$ A, $dI/dt \leq 140$ A/ μ s, $V_{DD} \leq V_{DS}$, $T_J \leq 150$ °C.
- 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	40	°C/W
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.24	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.45	

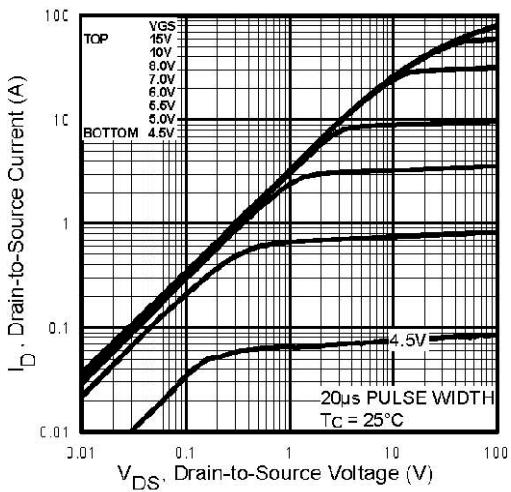
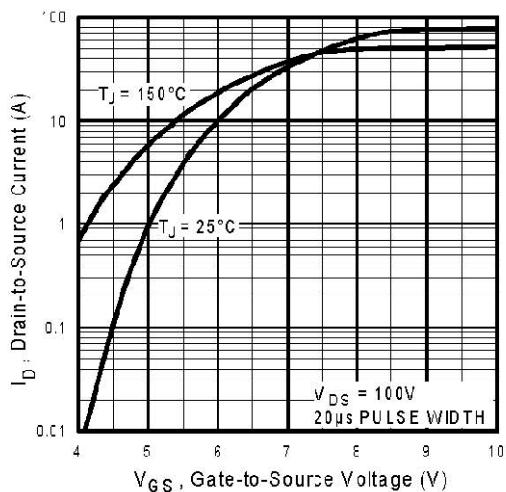
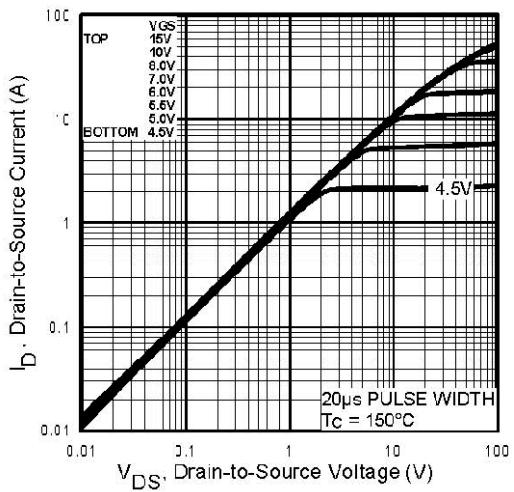
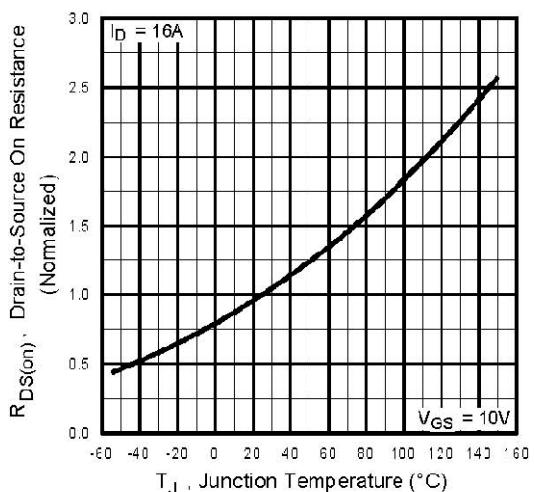
SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$		600	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$		-	0.63	-	$\text{V}/^\circ\text{C}$	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		2.0	-	4.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA	
		$V_{DS} = 480 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125^\circ\text{C}$		-	-	250		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 9.6 \text{ A}^b$	-	-	0.40	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 9.6 \text{ A}$		11	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	3500	-	pF	
Output Capacitance	C_{oss}			-	400	-		
Reverse Transfer Capacitance	C_{rss}			-	39	-		
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 16 \text{ A}$, $V_{DS} = 360 \text{ V}$, see fig. 6 and 13 ^b	-	-	120	nC	
Gate-Source Charge	Q_{gs}			-	-	29		
Gate-Drain Charge	Q_{gd}			-	-	48		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 300 \text{ V}$, $I_D = 16 \text{ A}$, $R_G = 4.3 \Omega$, $R_D = 18 \Omega$, see fig. 10 ^b		-	17	-	ns	
Rise Time	t_r			-	57	-		
Turn-Off Delay Time	$t_{d(off)}$			-	43	-		
Fall Time	t_f			-	38	-		
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH	
Internal Source Inductance	L_S			-	13	-		
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	16	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	64		
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}$, $I_S = 16 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	1.8	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}$, $I_F = 16 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$		-	650	980	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			-	6.0	9.0	μC	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics, $T_c = 25\text{ }^\circ\text{C}$

Fig. 3 - Typical Transfer Characteristics

Fig. 2 -Typical Output Characteristics, $T_c = 150\text{ }^\circ\text{C}$

Fig. 4 - Normalized On-Resistance vs. Temperature

IRFPC60LC, SiHFPC60LC

Vishay Siliconix

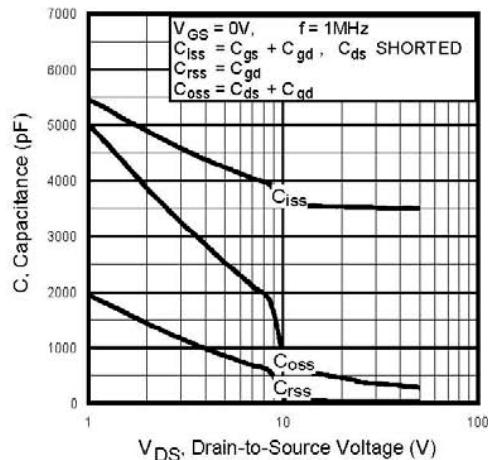


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

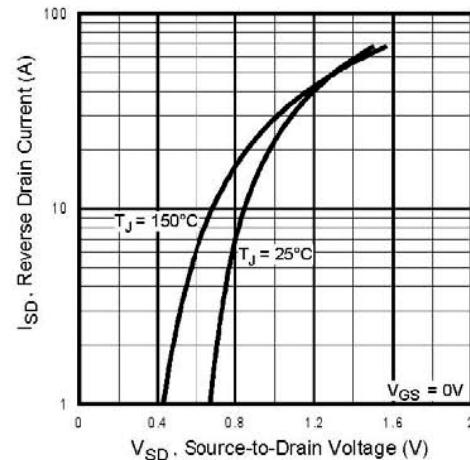


Fig. 7 - Typical Source-Drain Diode Forward Voltage

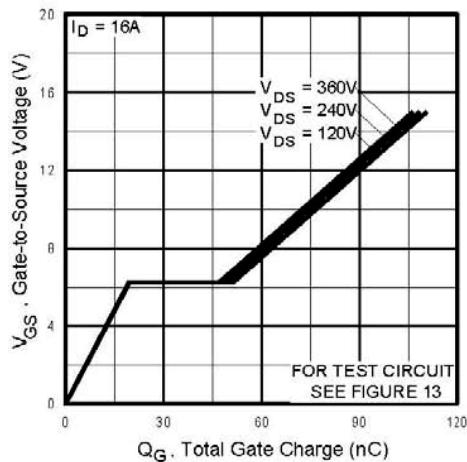


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

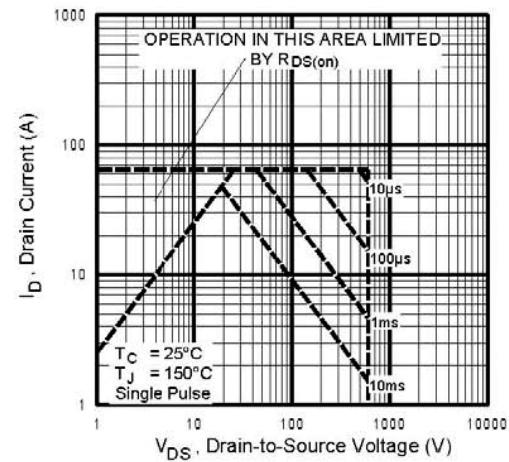


Fig. 8 - Maximum Safe Operating Area

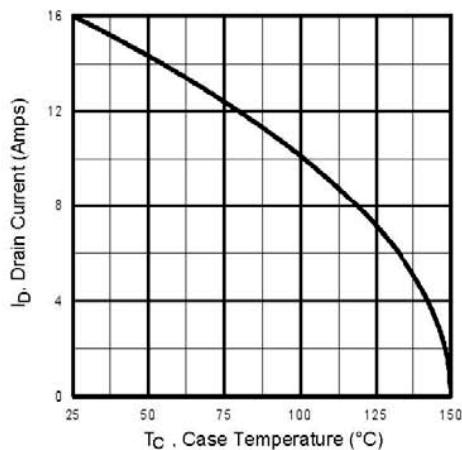


Fig. 9 - Maximum Drain Current vs. Case Temperature

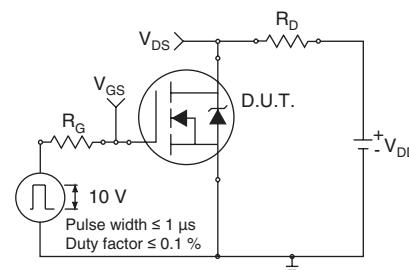


Fig. 10a - Switching Time Test Circuit

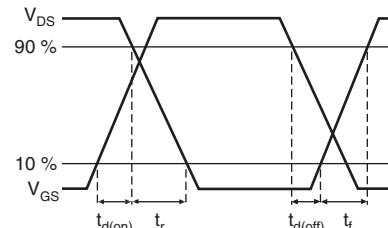


Fig. 10b - Switching Time Waveforms

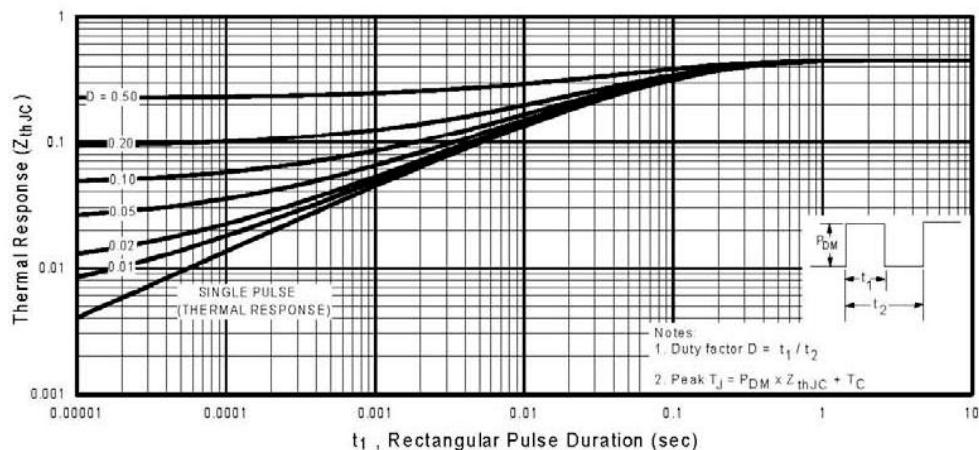


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

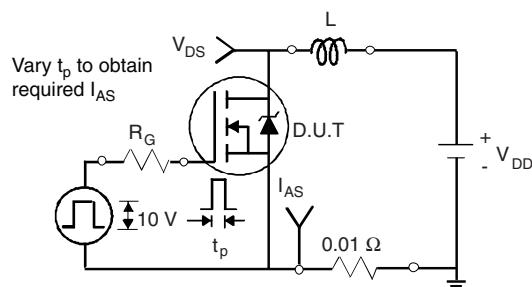


Fig. 12a - Unclamped Inductive Test Circuit

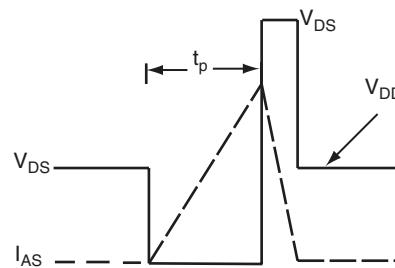


Fig. 12b - Unclamped Inductive Waveforms

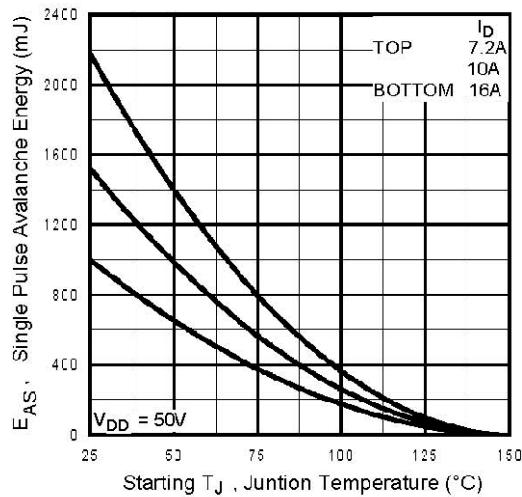


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

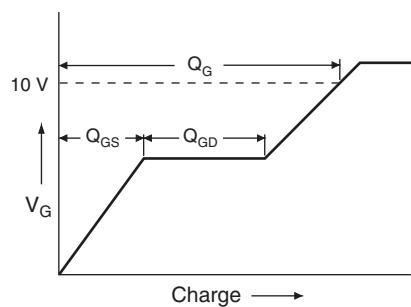


Fig. 13a - Basic Gate Charge Waveform

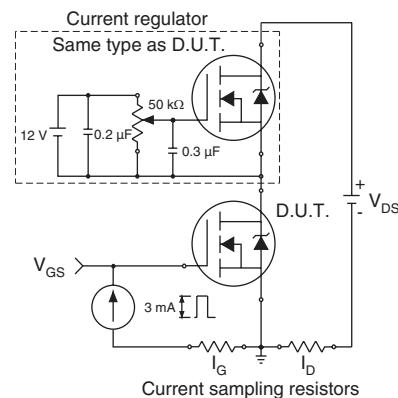
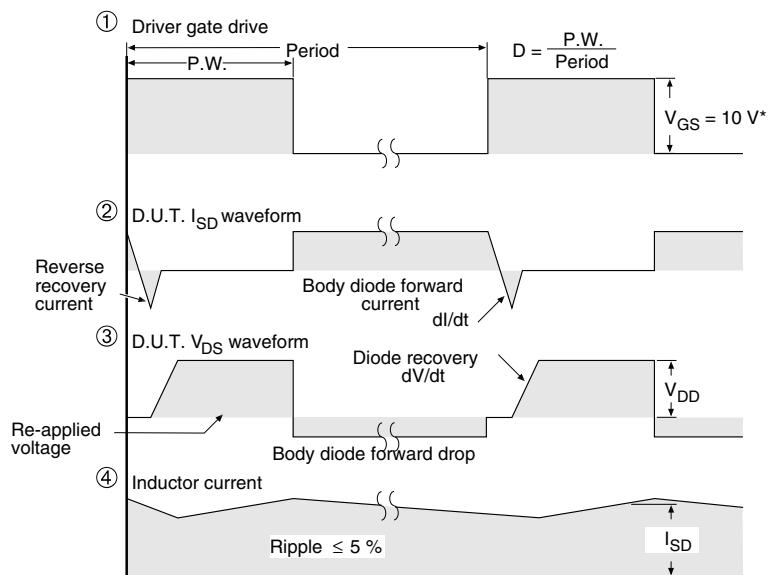
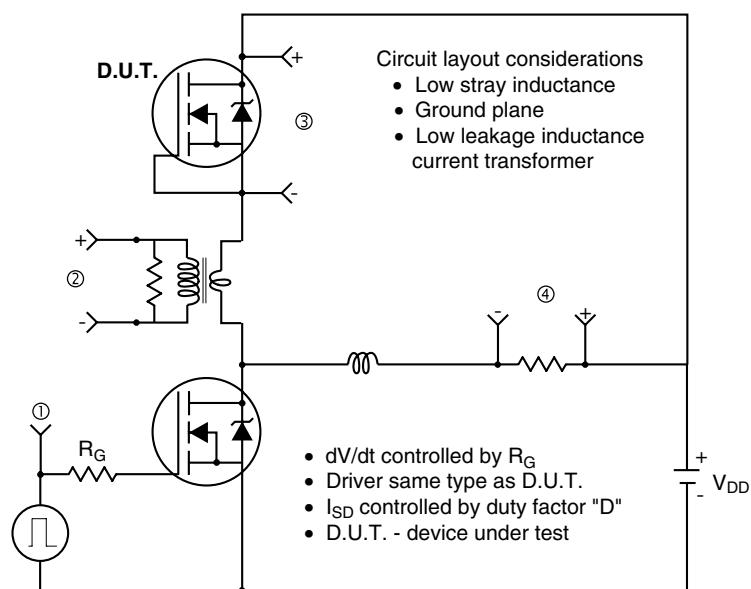


Fig. 13b - Gate Charge Test

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel

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